

# Search Notes



Application No.

10/706,090

Examiner

Granvill D Lee, Jr

Applicant(s)

SUGAMOTO ET AL.

Art Unit

2825

## SEARCHED

Class	Subclass	Date	Examiner
438	745,689	9/1/2004	GL
438	693,704	9/1/2004	GL
438	494,498	9/1/2004	GL
438	504	9/1/2004	GL
438	734-735	9/1/2004	GL
216	56,62	9/1/2004	GL
216	103-109	9/1/2004	GL
156	345.1	9/1/2004	GL
156	345.11	9/1/2004	GL
156	912-915	9/1/2004	GL
ABOVE	UPDATED	3/16/2005	GL
ABOVE	UPDATED	9/15/2005	GL

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
second solution, oxidative add, oxidizing agent, crystal defects, secco etch, cleaning, selective etching, HF, defect-free	9/1/2004	GL
UPDATED See EAST	3/16/2005 + 9/15/2005	Q Q